

## EC-80P NON-CONTACT TYPE SHEET RESISTANCE/RESISTIVITY MEASUREMENT

**EC-80P**



- Single Point, Non-Contact Type by Eddy Current method
- Auto-measurement start by probe head contacting to sample
- 3 measurement modes; wafer resistivity, bulk resistivity and sheet resistance
- Easy set up to measurement condition by JOG dial
- Measure Range depends on selected Probe Type

MEASURE RANGE					
PARAMETER	LOW PROBE TYPE	MIDDLE PROBE TYPE	HIGH PROBE TYPE	S-HIGH PROBE TYPE	SOLAR WAFER PROBE TYPE
RESISTIVITY ( $\Omega \cdot \text{cm}$ )	0.001 to 0.05	0.05 to 0.5	0.5 to 60.0	60.0 to 200.0	0.2 to 15.0
SHEET RESISTANCE ( $\Omega/\text{Sq}$ )	0.01 to 0.5	0.5 to 10.0	10.0 to 1k	1k to 3k	5 to 500

### APPLICABLE MATERIALS

- Semiconductor and Solar-cell materials (Silicon, Polysilicon, SiC etc)
- Functional materials (Carbon nanotube, DLC, graphene, Ag nanowire etc)
- Conductive thin film (Metal, ITO etc)
- Chemical compound semiconductor (GaAs Epi, GaN Epi, InP, Ga etc)
- Others: On Request

